

## -60V P-Channel Enhancement Mode MOSFET

### Description

The AP80P06P/T uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 6V. This device is suitable for use as a Battery protection or in other Switching application.

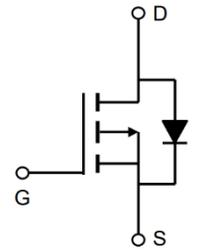
### General Features

$V_{DS} = -60V$   $I_D = -82A$

$R_{DS(ON)} < -12m\Omega$  @  $V_{GS} = -10V$  (Type: 10m $\Omega$ )

### Application

Lithium battery protection  
 Switching Mode Power Supply  
 UPS



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP80P06P	TO-220-3L	AP80P06P XXX YYYY	1000
AP80P06T	TO-263-3L	AP80P06T XXX YYYY	800

### Absolute Maximum Ratings ( $T_C = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-60	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-82	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-52	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	-328	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	450	mJ
$I_{AS}$	Avalanche Current	52	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	110	W
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	0.70	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	60	$^\circ\text{C/W}$

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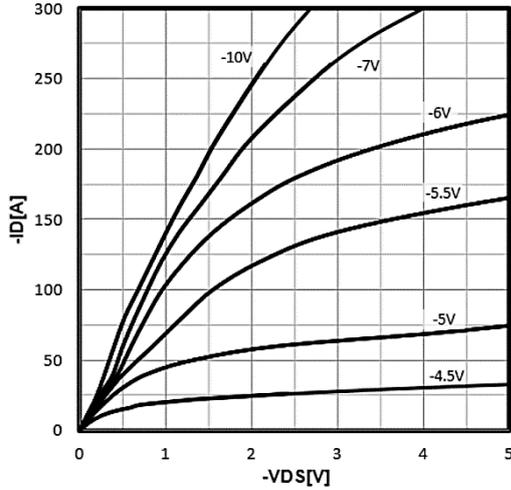
### Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA	-60	-68	---	V
ΔBVDSS/ΔT <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =-1mA	---	-0.035	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A	---	10	12	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-15A	---	13	16	
VGS(th)	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250μA	-1.0	-2.1	-3.0	V
ΔVGS(th)	VGS(th) Temperature Coefficient		---	4.28	---	mV/°C
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	---	---	1	μA
		V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	---	---	±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>D</sub> =-20A	---	50	---	S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	---	2.0	---	Ω
Q <sub>g</sub>	Total Gate Charge (-4.5V)	V <sub>DS</sub> =-30V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A	---	56	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	11	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	9	---	
Td(on)	Turn-On Delay Time	V <sub>DD</sub> =-30V, V <sub>GS</sub> =-10V, R <sub>G</sub> =3Ω, I <sub>D</sub> =-20A	---	4.5	---	ns
T <sub>r</sub>	Rise Time		---	2.5	---	
Td(off)	Turn-Off Delay Time		---	14.5	---	
T <sub>f</sub>	Fall Time		---	3.8	---	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, f=1MHz	---	3500	---	pF
C <sub>oss</sub>	Output Capacitance		---	600	---	
Crss	Reverse Transfer Capacitance		---	25	---	
I <sub>S</sub>	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current	---	---	-80	A
ISM	Pulsed Source Current <sup>2,5</sup>		---	---	-240	A
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =-1A, T <sub>J</sub> =25°C	---	---	-1.2	V

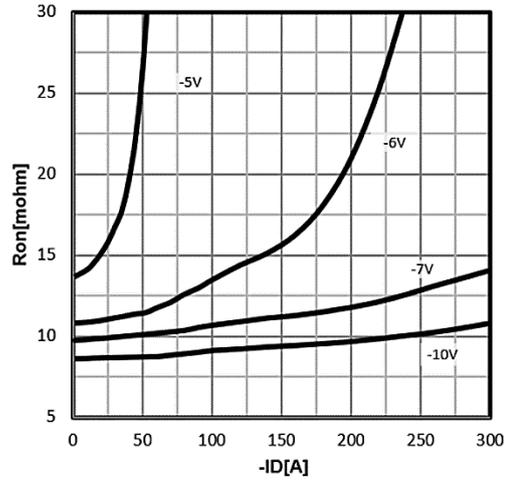
#### Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 20Z copper.
- 2、The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%
- 3、The EAS data shows Max. rating. The test condition is V<sub>DD</sub> = -48V, V<sub>GS</sub> = -10V, L=0.1mH, I<sub>AS</sub> = -52A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

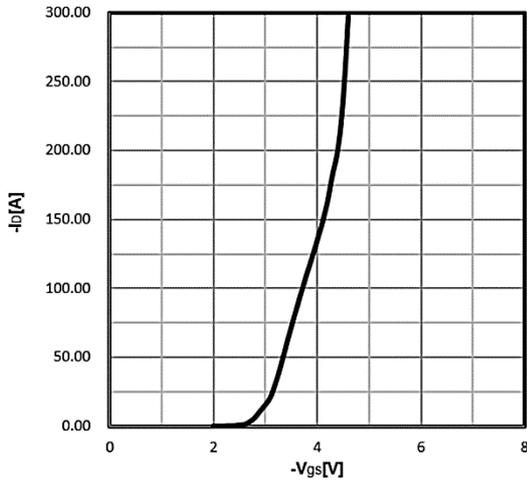
**Typical Characteristics**



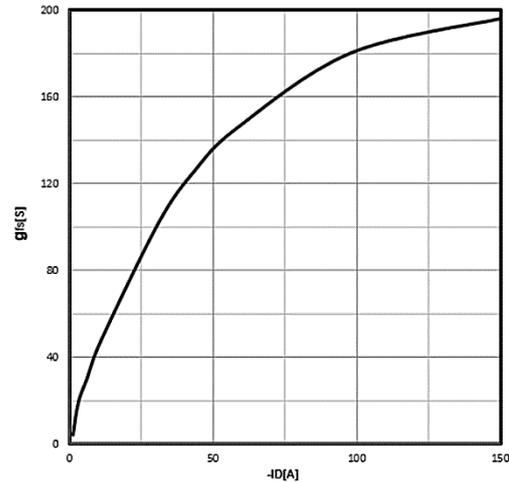
**Figure 1. Type. Output Characteristics ( $T_j=25\text{ }^\circ\text{C}$ )**



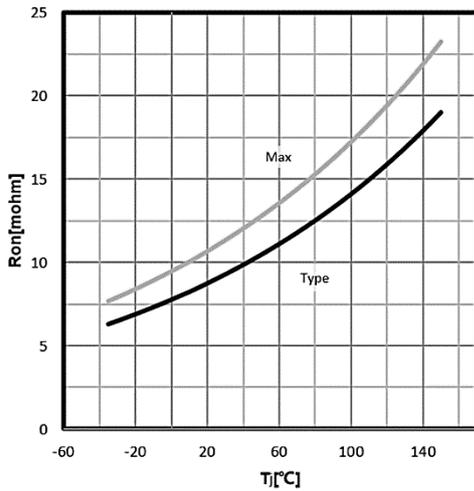
**Figure 2. Type. drain-source on resistance**



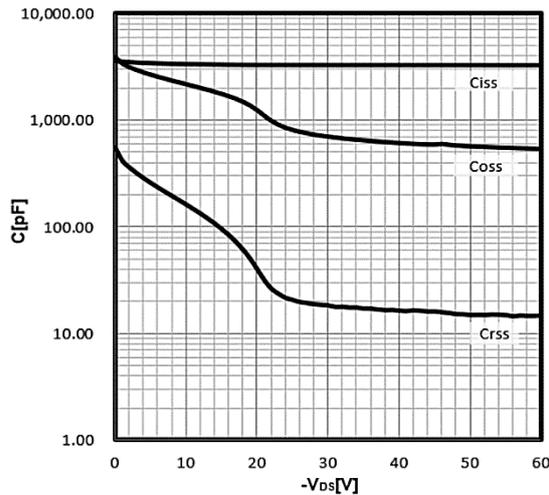
**Figure 3. Type. transfer characteristics**



**Figure 4. Type. forward transconductance**



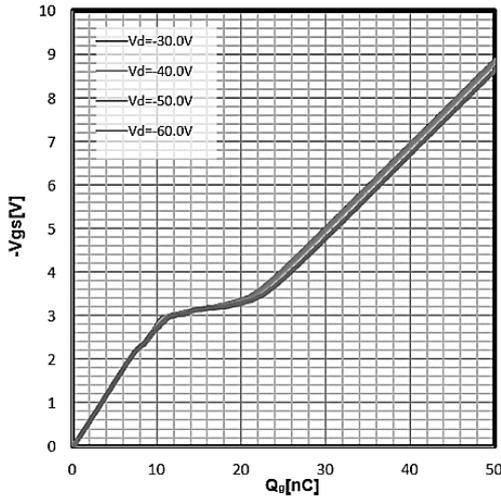
**Figure 5. Drain-source on-state resistance  $R_{DS(on)} = f(T_j)$ ;  $I_D = 80\text{A}$ ;  $V_{GS} = 10\text{V}$**



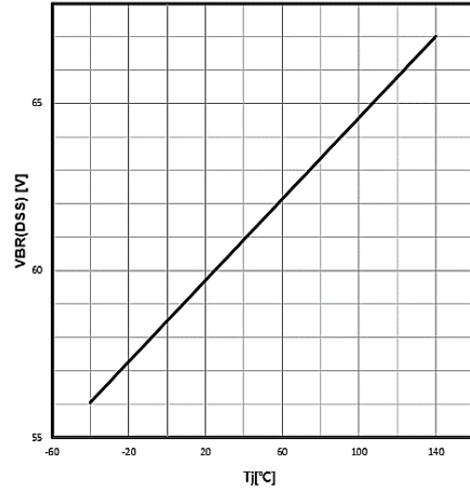
**Figure 6. Body-Diode Characteristics  $C = f(V_{DS})$ ;  $V_{GS} = 0\text{V}$ ;  $f = 1\text{MHz}$**



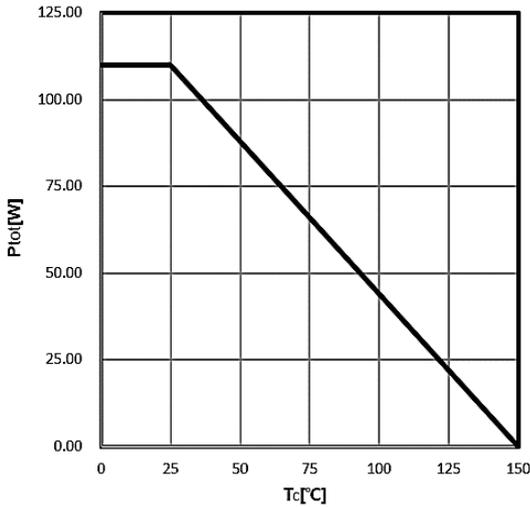
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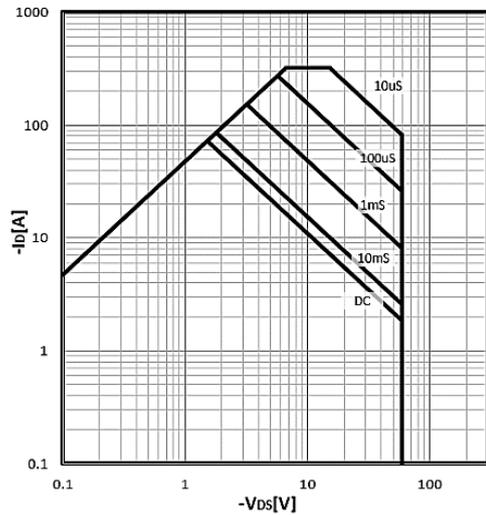
**Figure 7. Typ. gate charge**  
 $V_{GS} = f(Q_{gate})$ ;  $I_D = 20A$



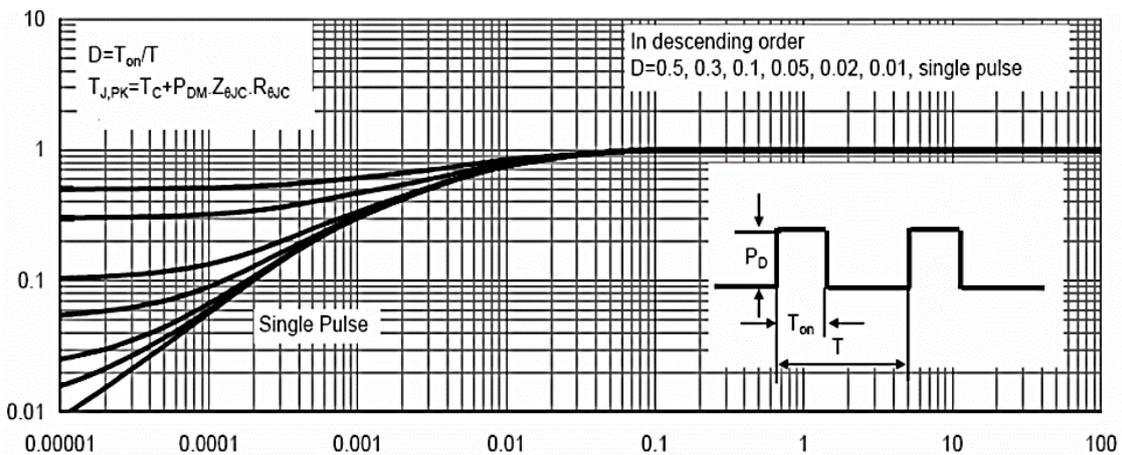
**Figure 8. Drain Current Derating**  
 $V_{BR}(DSS) = f(T_j)$ ;  $I_D = 250\mu A$



**Figure 7. Power Dissipation**



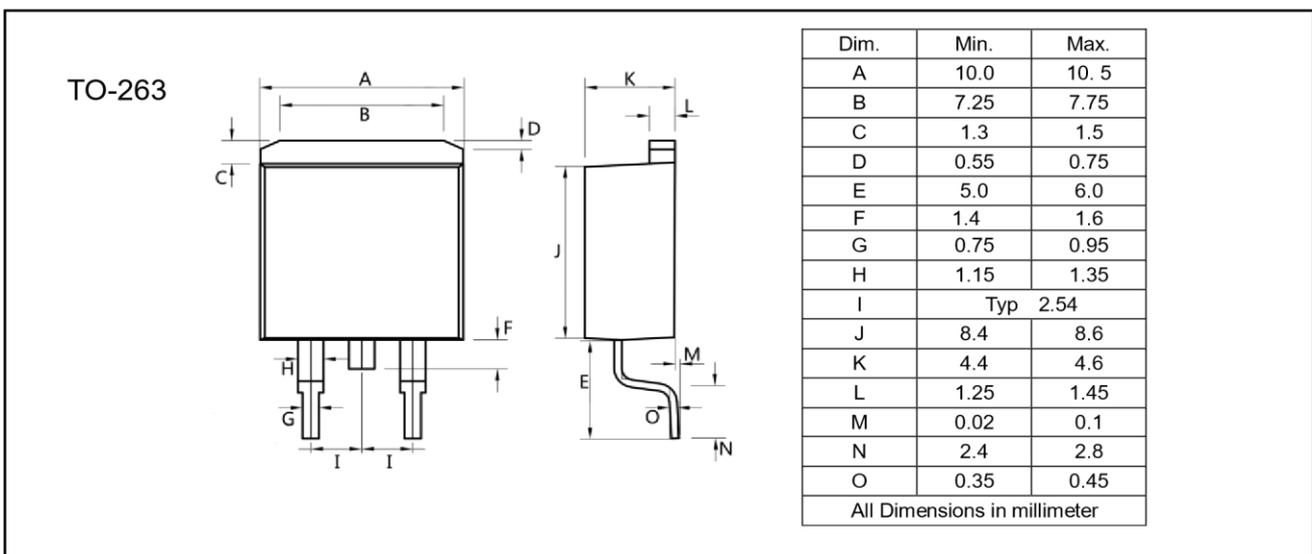
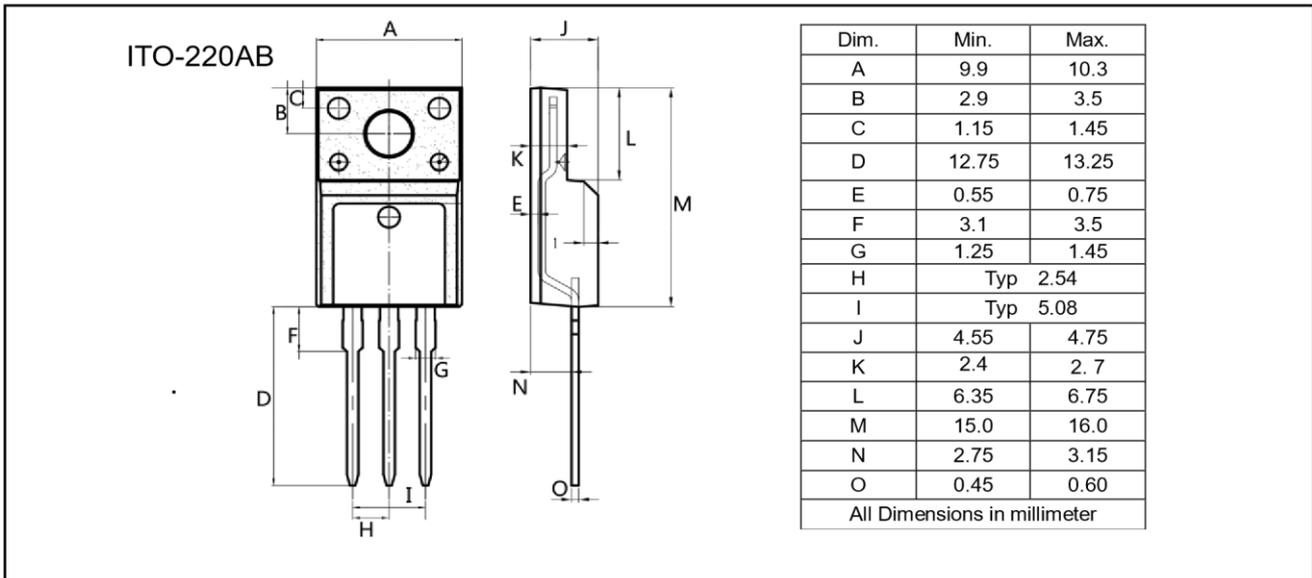
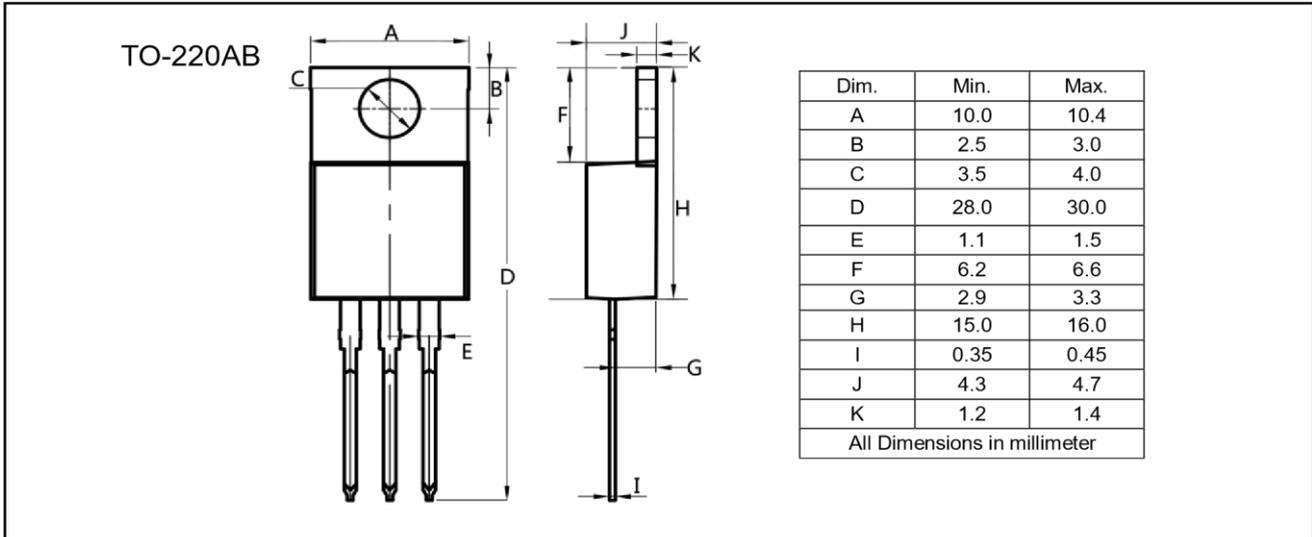
**Figure 8. Safe operating area**



**Figure 10. Max. transient thermal impedance**

$Z_{thJC} = f(t_p)$

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Edition	Date	Change
Rve1.0	2021/2/31	Initial release

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